OIPE JC139 JUL 14 2004 PATENT & TRADEMARK OFFICE

FORM PTO-1449 MODIFIED

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

Docket No.: 44046.203.96.3.9	Application No.: 09/868,542

APPLICANT: KRISKO, et al.

FILING DATE: May 14, 2002

GROUP ART UNIT: ~~1762~~ 1753

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

SHV	MikroElektronick – High-rate Sputtering System for Two-sided Coating (HZS-04)

EXAMINER SIGNATURE

DATE CONSIDERED November 2, 2004

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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SHN	Quotation Specification – August, 1988

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